

Examiner-Initiated Interview Summary	Application No.	Applicant(s)
	09/699,772	SUTARDJA, SEHAT
	Examiner Arnold M Kinkead	Art Unit 2817

All Participants:

(1) Arnold M Kinkead.

Status of Application: _____

(3) Mr. Eric Janofsky.

(2) Mr. Donald Daley.

(4) _____.

Date of Interview: 9 October 2003

Time: _____

Type of Interview:

Telephonic
 Video Conference
 Personal (Copy given to: Applicant Applicant's representative)

Exhibit Shown or Demonstrated: Yes No

If Yes, provide a brief description: _____

Part I.

Rejection(s) discussed:

Claims discussed:

all pending, notably 2,15, and 57

Prior art documents discussed:

Beards et al of record

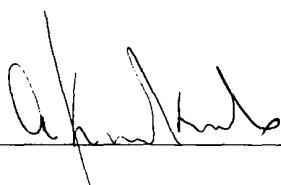
Part II.

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:

See Continuation Sheet

Part III.

It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.
 It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.



(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: The examiner reviewed the Beards et al reference, col. 4, lines 6-55, noting the fact that it does in fact suggest use of FET's and that the degeneration/attenuation capacitance is used to prevent low frequency noise, in FET's, this would inherently include flicker noise too. note fundamental frequency of 1000MHz is 10 times the 100MHz of the bandpass filter formed by the attenuating device and amplifier(l1. 35-40). 112, 2nd para issues resolved for claims too. (see exam. amdt.)